Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/721,673	QIN ET AL.
Examiner	Art Unit
Phallaka Kik	2825

SEARCHED					
Class	Subclass	Date	Examiner		
716	2,3,5,6,13, 14,7	7/21/2006	PK		
Above	New	8/5/2006	PK		
Above	New	8/8/2006	PK		
Above	updated	2/17/2007	PK		
			-		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
716	2,3,5,6	2/17/2007	PK		
716	13,14,7	2/17/2007	PK		
USPGPUB (see attached)		2/17/2007	PK		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
BRS (EAST)USPAT, USPGPUB Class/Sub searched: 716/1-18; 703/2,14-16 (see attached)	7/21/2006	PK		
EPO, JPO, IBM TDB, Derwent (see attached)	7/21/2006	PK		
IEE/IEEE Xplore (see attached)	7/21/2006	PK		
All above new search (see attached)	8/5/2006	PK		
All above new search (see attached)	8/8/2006	PK		
All above updated search (see attached)	2/17/2007	PK		